Calibration of the length of a chain of single gold atom s

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U sing a scanning tunnelling m icroscope or m echanically controllable break junction it has been shown that it is possible to control the form ation of a wire m ade of single gold atom s. In these experiments an interatom ic distance between atoms in the chain of 3.6 A was reported which is not consistent with recent theoretical calculations. Here, using precise calibration procedures for both techniques, we measure the length of the atom ic chains. Based on the distance between the peaks observed in the chain length histogram we nd the mean value of the interatom ic distance before chain nupture to be 2.5 0.2 A. This value agrees with the theoretical calculations for the bond length. The discrepancy with the previous experimental measurements was due to the presence of H e gas, that was used to promote the therm al contact, and which a ects the value of the work function that is commonly used to calibrate distances in scanning tunnelling m icroscopy and m echanically controllable break junctions at low temperatures.

INTRODUCTION

In the last few years, there has been a signi cant advance in the understanding of the electronic properties of atom ic-sized contacts. This has been possible thanks to the use of two techniques: the scanning tunnelling microscope (STM)[1, 2] and the mechanically controllable break junction (M C B J) β]. In both cases the distance between two electrodes is controlled by means of a piezo-electric transducer which allows for relative displacements of the electrodes down to a resolution in the range of picom eters.

In these experiments the current that traverses the contact between two electrodes, at a given bias voltage, is measured as a function of the relative displacement of these electrodes. As the contact is broken, the current changes smoothly during elastic elongation stages, decreasing suddenly in plastic deformations stages[4, 5]. In the last stage before breaking the contact, just a few atoms determine the electronic transport and the conductance is given by the Landauer form ula

$$G = \frac{2e^2}{h} \prod_{n=1}^{X^N} T_n :$$
 (1)

Here, N is the number of available channels for the electrons traversing the contact, e is the electron charge, h is P lanck's constant, and T_n is the transm ission probability of the nth channel. Just before the contact is broken, when there is just a single atom at the contact, the conductance for monovalent metals, such as gold, has been shown [6] to be due to a single conductance channel with transm ission probability close to unity and therefore with a conductance close to the value $2e^2=h$.

It was observed that occasionally the conductance of the one-atom contact for gold rem ains constant while the distance between the two electrodes increases by more than an interatom ic distance, as it is shown in Fig. 1. W hen it nally breaks, in order to make contact again it is necessary to decrease the interelectrode distance by the same distance. From such observations it was concluded that in these cases a wire only one atom thick was form ed between the two electrodes [7]. These wires have also been observed by transm ission electron m icroscopy (TEM)[8,9]. The Au-Au bond length was reported to be 3.6 A (30%) and 3.6{4.0 A in [7] and [8] respectively. It was recently shown that, apart from Au, chain formation can be observed in Pt and Ir [10, 11]. In this paper we concentrate on Au contacts. Several calculations have con m ed the possibility of the form ation of an atom ic chain of gold atom s when stretching the

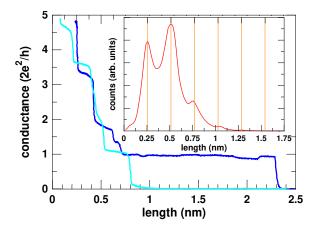


FIG.1: Evolution of the conductance for a gold contact as a function of the interelectrode distance recorded with the MCBJ technique. The last plateau of the conductance corresponds to an atom ic chain of about six atom s long. The inset shows a histogram made from 10000 recordings of the last plateau length obtained from individual conductance curves taken at 4.2 K in vacuum.

m onatom ic contact [12, 13, 14, 15, 16]. However, in all cases a large discrepancy with the reported experimental bond length (3.6 A) was found. The calculations use di erent methods including ab initio calculations using the local-density approximation [13, 14, 15, 17, 18] and molecular-dynamics simulations using elective-medium theory [12] or tight-binding approximations [16]. For the wire's equilibrium bond length the dierent calculations give a distance between 2.32 and 2.55 A, and an upper limit after stretching of 3.0 A, much smaller than the one reported in the experiments.

In this paper we show how the interatom ic distance in these atom ic wires can be estimated from the conductance vs electrode displacement curves. Using this method we obtain for gold chains at low temperature (4.2 K) an interatom ic distance of 2.5 0.2 A at the average maximum tensile stress at the moment of fracture.

CALIBRATION METHODS

Since the separation between the peaks in the length histogram can provide inform ation on the bond distance in the chains it is crucial to have a good calibration of the displacement of the electrodes as a function of the voltage which is applied to the piezo element of the STM or M CBJ. The various methods that we have used to calibrate our STM and M CBJ are described below.

Tunnelbarrier

The exponential dependence of the current on the vacuum gap can be used to make a rough calibration in STM, and until very recently [20] it was the only way to obtain a calibration of the interelectrode displacements in the MCBJ. One makes use of the well-known dependence of the tunnel current I_T between two electrodes which are separated by a distance d, when a small voltage V_0 smaller than the work function of the electrodes is applied [21],

$$I_{T} (V_{0}) = K V_{0} e^{2d^{\frac{p}{2m}} = h^{2}};$$
 (2)

where m is the mass of the electron, is the height of the tunnel barrier, approximately given by the mean value of the work function of the two electrodes, K is a constant which is related to the area of the electrodes and to the electronic density of states at the Ferm i level.

The exponential dependence of the tunnel current with the interelectrode distance makes it very easy to control that distance and this is the basis of operation of the STM. If we represent on a semilog scale the variation of the current as function of the voltage V_p applied to the piezo element (see Fig. 2) for the slope we obtain the

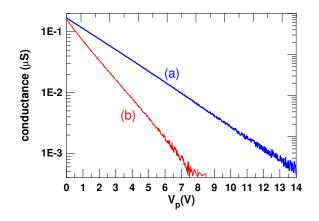


FIG.2: Exponential dependence of the current as function of the piezo voltage at a xed bias voltage V = 100 mV when the two electrodes are separated by a tunnel barrier in vacuum (a) or in a He atm osphere (b).

following expression:

$$= \frac{p \frac{2m}{2m}}{h} \frac{2 d}{V_{P}}; \qquad (3)$$

This immediately gives us a calibration of the distance as

$$= \frac{d}{V_p} = \frac{p}{2^p 2m} : \qquad (4)$$

This expression is very simple and indeed in experiments with clean electrodes an exponential behavior of the current as a function of V_P is found, which would make this a suitable method for calibration of the response of the system to the voltage applied to the piezoelectric transducer. A lthough a more realistic description for the tunnel barrier must include electron screening elects, it has been argued [22] that these elects nearly cancel in the logarithm ic derivative, at least for not too small distances.

A problem that arises when using this method is that the value of the tunnel barrier is dependent on the local work function of the closest parts of the two electrodes. This local work function depends mainly on the material with som e variation due to surface distortion and crystal orientation [e.g., the work function for gold in the (100) direction is 5.47 eV while for the (111) direction it has a value of 5.31 eV [24]]. However, the largest deviation is due to the use of helium . Helium gas is commonly used to prom ote therm al contact for cooling of the STM or M C B J. It was generally believed that helium gas does not signi cantly in uence the electron tunneling between two metallic electrodes. However, very recently it has been found that atom ic layers of adsorbed helium can a ect dram atically the work function measured with this technique [23]. Since the apparent work function was seen to increase for a He pressure of only 0.01 Torr by 80%

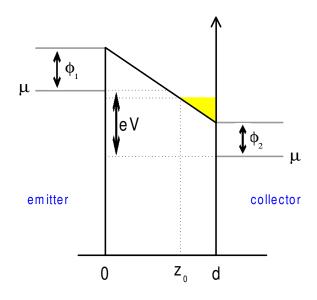


FIG.3: Energy diagram for eld-emission oscillations. Horizontal: z coordinate parallel to the current direction. Vertical: energy. $_1$ is the work function for the left electrode and $_2$ that for the right electrode. The chemical potential for the two electrodes are shifted by the applied voltage eV.

above the clean surface value, errors of up to 34% are introduced in the distance calibration due to the presence of a helium atmosphere. For this reason, in the MCBJ experiments described below we avoid using helium as a therm all exchange gas.

Gundlach oscillations

A di erent m ethod for calibrating the M C B J, based on the G undlach oscillations, has been developed by O Yu. K olesnychenko et al. [20]. The G undlach oscillations [25], or eld-em ission resonances, are observed in the tunnel conductance when a voltage higher than the work function of the electrodes is applied between them.

As illustrated in Fig. 3 when the applied voltage V across the tunnel junction is larger than the work function of the electrodes, $_{1;2}$, part of the barrier region becomes classically accessible. In this case the wave function of the electrons in the region between the electrodes will be determined by the superposition of the incoming and relected waves at the interfaces. This mechanism will give rise to periodic maxim a of the transmission as a function of bias voltage when new resonant states are formed between the electrodes. U sing the model for this problem proposed by G undlach [25], K olesnychenko et al. obtained an expression for the dilerential conductance as a function of bias voltage given by

$$\frac{dI(V)}{dV} = A(V)\cos[d(V)];$$
 (5)

The amplitude of the oscillations, A (V), decreases with voltage as V $^{3=2}$ and the argument for the cosine function is given by

$$_{d}(V) = \frac{4}{3} \frac{p \frac{2m}{2m}}{h} \frac{(eV_{2})^{3=2}}{eF};$$
(6)

where F is the electric-eld strength in the vacuum gap. The relation between the peak position V_n of the oscillations in Eq. (5) and their index can be found by equating Eq. (6) to 2n:

$$eV_n = {}_2 + \frac{3}{2} \frac{h}{2m} F^{2=3} r^{2=3} n^{2=3}$$
: (7)

D uring the experiment we keep F constant by applying a feedback to the piezo voltage in order to maintain the current constant. From a plot of V_n versus $n^{2=3}$ the work function is obtained as the intercept at the voltage axis and from the slope of the curve we obtain the eld strength

$$F = \frac{2^{p} \overline{2m}}{3 h}^{3=2} :$$
 (8)

The distance between the two electrodes will then be related to F and the applied bias voltage according to

$$d = \frac{1}{eF} (eV +);$$
 (9)

where is the di erence in the work function between the two electrodes. U sing these expressions the procedure to make the calibration using the G undlach oscillations will be as follows: we record the evolution of the conductance, as well as the piezo voltage V_p , as a function of the applied bias voltage while keeping the current constant (see Fig. 4). Then using Eqs. (7) and (8) we can calculate the eld strength F ' 1:087 ³⁼² [V /nm]. Finally using Eq. (9) and the response of the feedback to the voltage changes applied to the junction we can obtain

$$= \frac{d}{V_p} = \frac{1}{F} \frac{V}{V_p}$$
(10)

for the response at high voltages, where the variation is approximately linear.

Interferom etric calibration

The interferom etric calibration is a very accurate m ethod for distance calibration. We have used an allber interferom eter sim ilar to those used in atom ic force m icroscopy [26] to calibrate our STM used in the experim ents on atom ic chains. A scheme of the experimental set up is shown in Fig. 5. The tip is fastened to a z positioner which is m oved by four stacks of shear piezos. To calibrate the displacement of the z positioner, the light

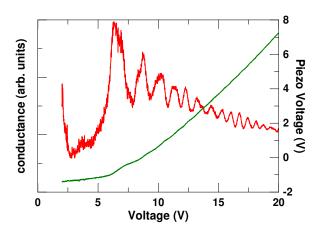


FIG. 4: Evolution of conductance and piezo voltage as the applied voltage across the tunnel junction is increased, while keeping the current constant. The analysis of this curve gives a value of 5.3 eV for the tunnel barrier indicating that the surface is free of adsorbates.

from a laser diode is focused into a single mode optical ber and transm itted through a 2 2 directional coupler which splits the beam. Part of the light is coupled to a reference photodiode which measures the intensity of the laser beam. This intensity is the one used as reference when focusing the light. The remainder of the beam is transm itted to the end of the berwhich is placed close to a mirror glued to the rear of the z positioner. In this way an interferom etric cavity is formed between the ber end and the mirror. About 95% of the beam that reaches the ber end is transm itted, then rejected at the mirror and directed back into the ber, interfering with the beam rejected at the ber end. The optical path dif-

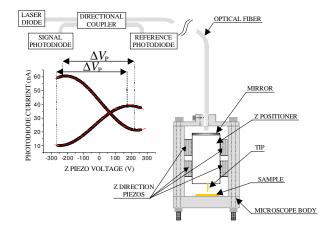


FIG.5: Experim ental setup for the STM con guration. The displacem ent of the tip against the sam ple is calibrated by an interferom etric m ethod which reliability and accuracy rem ain una ected by the environm ent. The inset shows two di erent traces of the interference pattern m easured with di erent initial interferom eter cavity lengths.

ference between both beam s twice the interferom etric cavity length | m akes the intensity of the resulting beam to be given by

$$I = A + B \cos(4 d = +);$$
 (11)

where d is the interferom eter cavity length, A and B are constants that decrease with d, and is the wavelength of the laser beam, 660 nm. The calibration is perform ed by approaching the z positioner to the ber until the intensity detected by the signal photodiode is su ciently large. In order to vary linearly the cavity length, a voltage ram p is applied to the z direction piezos while the photocurrent of the signal photodiode is m easured. Two typical calibration m easurem ents, with di erent initial interferom eter cavity lengths (and therefore with di erent m ean intensities) are shown in the graph in Fig. 5. For a voltage span V_p , the interference pattern traces a sem iperiod. From Eq. (11), it follows that the ratio between the displacem ent and the applied voltage is

$$= \frac{d}{V_p} = \frac{1}{4 V_p}$$
(12)

EXPERIM ENTAL RESULTS

For the experim ents we have used gold sam ples of better than 99.9% purity. For the STM experiments we have cleaned the sam ple with an $H_2O - H_2SO_4$ (1:3) solution and mechanically sharpened the tip, while for the M CBJ a fresh surface was formed at cryogenic vacuum when breaking the sam ple. The experiments were all performed at 4.2 K. The conductance curves, from which the plateau lengths are obtained, are all measured at a constant bias voltage of 10 m V.

In Fig.1 we show a typical experiment were an atom ic chain is formed with the inset showing a histogram of last-plateau lengths. We have obtained length histogram swith both STM and MCBJ.

A large num ber of indentation-elongation cycles of gold nanocontacts was made. Special attention was given to include a large num ber of atom ic con gurations in the statistics, forcing structural rearrangements of a large num ber of atom s with frequent deep indentations of several hundreds of nanom eters between cycles.

In the case of the MCBJ we have measured for several samples plateau length histogram s and each of them was calibrated by both the tunnel barrier method and by means of the Gundlach oscillations. For the tunnel barrier method we have taken a work function for gold of 5.4 eV. In this case the standard deviation in the distribution of calibration values results into an error of 7%. Using this calibration we obtain for the interpeak distance in the length histogram a value of 2.5 0.2 A. The calibration using the Gundlach oscillation method was ham – pered most of the times by multiple tip e ects in the eld

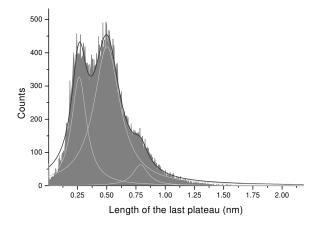


FIG. 6: Histogram of lengths for the last conductance plateau obtained in 65000 indentations made with the STM. We de ne the length of the last plateau as the distance between the point where the conductance drops below 1.2 times the conductance quantum and the one where the contact breaks.

resonances and the response of the feedback to the applied voltage often had a very in portant quadratic term. Such complication appears to be characteristic for gold [23] and the method works better form ost other metals. A sa result, we estimate the error in the calibration to be of the order of 20% and obtain for the interpeak distance 2:3 0:4 A.W e veri ed that the calibration obtained by the tunnel barrierm ethod after adm itting H e gas into the chamber shifts the peak distance to 3.3 A in agreement with [7].

In the case of the STM con guration, the calibration has been carried out by the interferom etric m ethod. This m ethod has the advantage of being independent of tip and sample conditions. U sing di erent lengths of the interferom eter cavity, a value of $= 3:70 \quad 0.13 \text{ A/V}$ is obtained. The experim ents were all perform ed alternating the conductance with the calibration m easurem ents every 15000 nanocontacts, while the instrum ent is m aintained at 4.2 K in vacuum. In Fig. 6 we show the resultant length histogram from the STM m easurem ents. W e nd here again a preference for contacts with one atom in cross section to break at speci c values of length with a periodicity of 2:6 0.2 A.

DISCUSSION

The linear bond between two gold atom s is up to three tim es stronger than a bulk bond, as found in experim ents and simulations [11, 19, 27]. A single-atom gold contact can sustain a maximum tensile force of 1.5 nN and before this limit is reached it is likely that atom s are pulled out of their position in the banks on either side of the contact. By repeating such atom ic structural changes in the banks the one-atom contact evolves into a chain several atom s long. The chain nally breaks when the tensile force necessary to incorporate another atom from the nearby electrodes into the chain is higher than the breaking force of the chain itself. There will be characteristic interelectrode distances for which a chain of n atom s is likely to break, as we will argue next.

Let us rst discuss a length histogram for m etals that do not easily form atom ic chains, such as the 4d m etals Rh, Pd, and Ag investigated in Ref. [10]. For these metals the length histogram shows only a single peak, usually at a shorter length than the rst peak in the length histogram for Au. We start counting the length of the plateau when the conductance drops to a typical value for a single atom contact, e.g., below $1.2G_0$ for Ag. W hen pulling further the conductance remains roughly at this value while the bonds of the atom with the banks and those inside the banks are being stretched. As soon as the stored elastic energy reaches a maximum the contact breaks. The breaking point depends on the local atom ic con gurations in the banks near the contact and this leads to a certain width in the peak distribution. Therm all activation over the breaking barrier will also lead to a statistical distribution of observed values. The peak position in the length histogram shows the most probable length over which a one-atom contact can be stretched.

For chain-forming metals such as Au the rst peak in the length histogram has the same interpretation as for those that break at a one-atom contact. Its position is at a longer length re ecting the stronger bond for lowcoordination Au atom s. For all con gurations giving rise to the distribution under the st peak there are equivalent con gurations with the central atom replaced by two, three, or more atoms, forming a chain. These will give rise to additional peaks in the length histogram at multiples of the Au-Au bond distance in the chains, but stretched close to the breaking point. These distances are the ones at which the structure reaches the maximum tensile stress while it is not possible to introduce a new atom into the chain to relax it. If we consider that the force needed to break an atom ic chain, F_{b} , is independent of the length of the chain [28] then the interelectrode distance at which the n-atom s chain breaks can be written as

$$L_{n} = nL_{at at} + (n + 1)\frac{F_{b}}{K_{a}};$$
 (13)

were L_{at} at is the interatom ic distance when no tension is applied and K_a the elastic constant of the bond between atom s in the chain. Therefore the distance between the peaks in the plateau length histogram will be constant and equal to $= L_{at} _{at} + F_{b} = K_{a}$, or in other words, equal to the interatom ic distance stretched to the point of breaking.

In this argum entation we have assumed that the banks

are not shortened between the point at which the conductance rst is seen to drop to the one-atom level and the nalbreaking point. As long as we lim it the discussion to chains of only a few atoms in length this will be correct since the number of atom ic layers in the banks will not be modied. Note that our value for the bond distance is based on the rst two to four peaks and that atom s may fold in from both sides. Those events that result in a signi cant modi cation in the structure and e ective length of the banks will only contribute to a sm ooth background in the length histogram . Only the chain-form ing processes that conserve the structure of the banks are expected to be responsible for peaks at regular spacing in the length histogram , and these are thus expected to correspond to the atom -atom distance in the chains. The Au-Au distance is measured from the distance between the peaks in the histogram, and we remark that the position of the rst peak (relative to zero length) can di er from this value. For Au the rst peak is nearly equal to the distance between the peaks, but di erent values have indeed been obtained, e.g., in the case of Pt chain length histogram s [10].

The bond distance near the anchoring points of the chain to the banks are expected to be about 10% shorter than the bond distance in the middle of the chain, as illustrated in the calculations by da Silva et al. [16]. A sm all variation in the bond length is consistent with our data, as can bee seen from the position of the fourth peak in Fig. 1. The fact that we derive our values for the bond distance mainly from the rst three peaks in plies that our result is biased toward the sm aller distances at the anchoring points.

The interatom ic distance for gold atom ic chains quoted 30% was a ected by calibrain Ref. [7] as 3.6 A tion inaccuracies in two ways: a system atic error in the calibration due to He exchange gas condensed onto the gold surface, resulting in an overestim ate of the Au-Au distance. In addition, variations between various calibrations, which is relected in the large uncertainty for the Au-Au distance. We have now used three independent techniques for an improved calibration with an accuracy of approximately 7% for two of them, the interferom etric m ethod for the STM and the tunnel barrier method for the MCBJ, which show consistence between these techniques and gives a more accurate value of the bond distance in a chain form ed by gold atom s. The calibration procedure with the largest error makes use of the Gundlach oscillations and gives a som ew hat sm aller, but consistent, value. However, there is still a problem of consistency with the results of H.Ohnishi et al. [8] and Rodrigues and Ugarte [9] who report an interatom ic distance of about 3.3{4.0 A obtained from TEM images. The discrepancy could be due the di erent methods used to fabricate the chains or the di erence in tem perature and environmental conditions. It has been recently pointed out that there exists a possibility of incorporating

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one oxygen atom per gold atom in an atom ic chain [29]. This addition should give rise to a gold-oxygen nanochain with a Au-Au distance of 3.8 A for a relaxed chain and up to more than 4.2 A for a stretched one. This kind of chain should exhibit a conductance of one quantum unit.

CONCLUSIONS

W e have applied di erent calibration techniques for the M CBJ and STM in order to obtain a more accurate value for the distance between peaks in length histograms of the last plateau of conductance before rupture of gold contacts at low temperature. The values obtained for the interatom ic distance in a chain of gold atoms at the point of breaking are 25 02,23 0.4, and 2.6 02 A. W e obtain an overall value for the interatom ic distance of 2.5 0.2 A, which closely agrees with results from m odel calculations.

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